

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/695,244	CHIN ET AL.
	Examiner	Art Unit
	Hsien-ming Lee	2823

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438	106, 110	9/28/5	Lee
438	113, 460		
438	463, 464	↓	↓